

Erratum

Erratum to ‘Effect of fluoride contamination on the growth of ZrO_2 films’ [J. Nucl. Mater. 250 (1997) 200–215] ¹Brian Cox ^{*}, Yin-Mei Wong, Philippe Dume ²

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In the final printed version of this paper, the corrections as given by the authors were not carried out. The most important of those corrections are as follows.

(1) Fig. 1. In the caption, the description of parts (c) and (d) should be transposed. Thus, the caption should now read:

Fig. 1. Scanning electron micrographs of a pickle-stained specimen after 7 days in 300°C, 3.5 MPa steam. (a) Stereo-pair of oxide adhering to metal after extraction of

surface oxide with sticky tape. (b) Stereo-pair of the same area of oxide adhering to the sticky tape. (c) Micrograph of surface of oxide film. (d) Large oxide platelets formed after 7 days in 0.1 MPa steam.

The figure can be viewed on the following page.

(2) 4.1. *Films on as prepared surfaces*. The citation of Fig. 6b in line 8 of paragraph 1 of this section should be of Fig. 4c.

(3) References. References [37–40] should be deleted.

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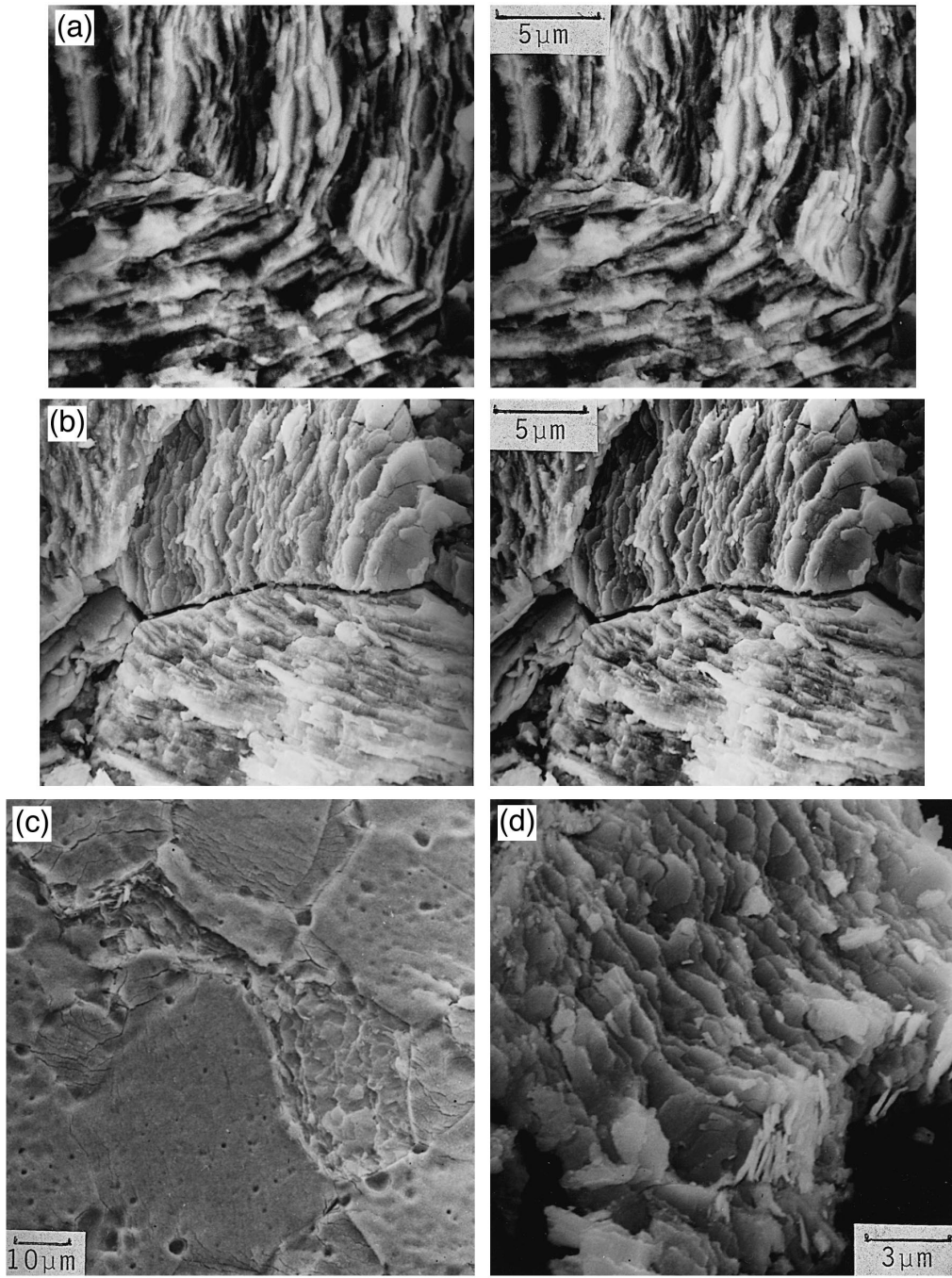


Fig. 1. Fig. 5 of the original paper. See the previous page for the full caption.